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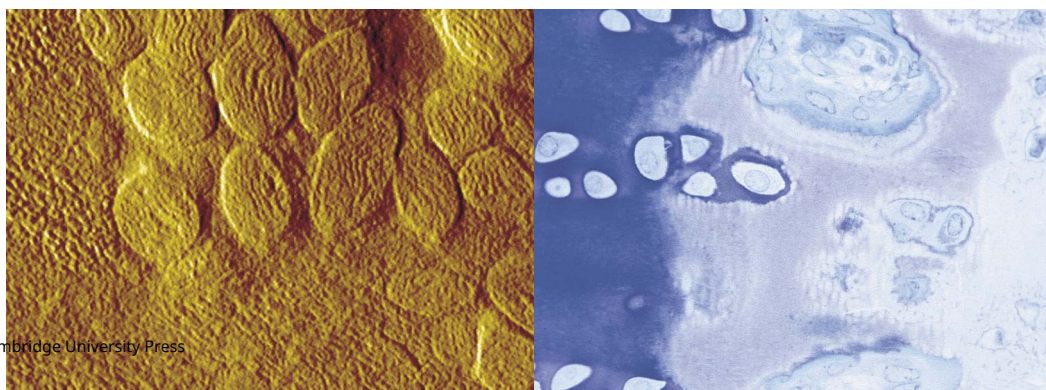
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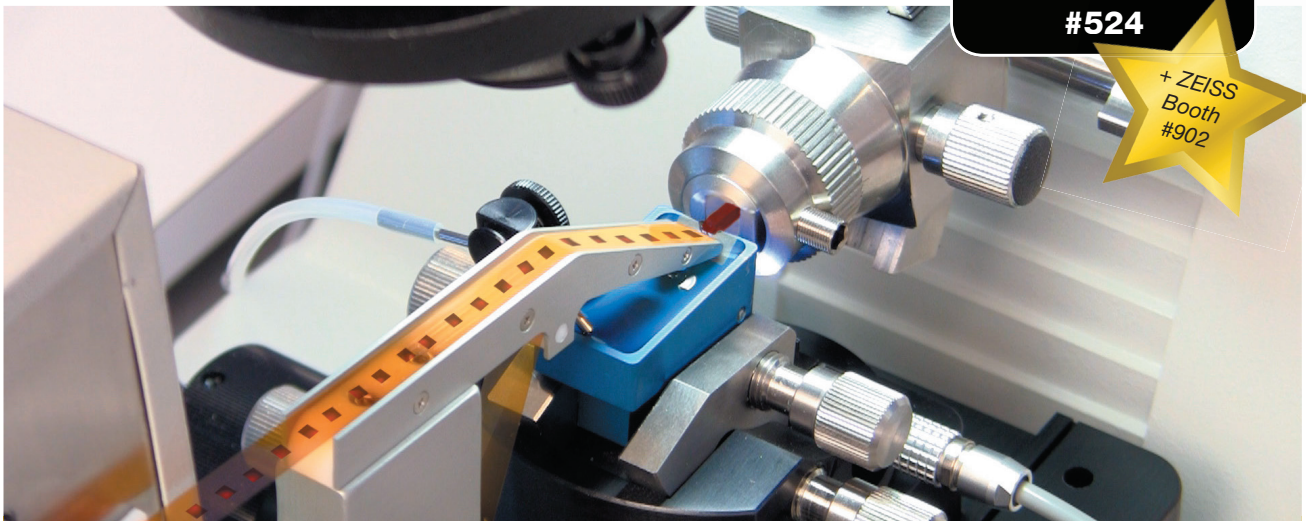


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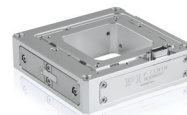
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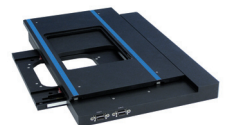
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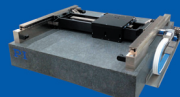
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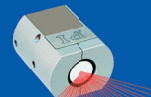
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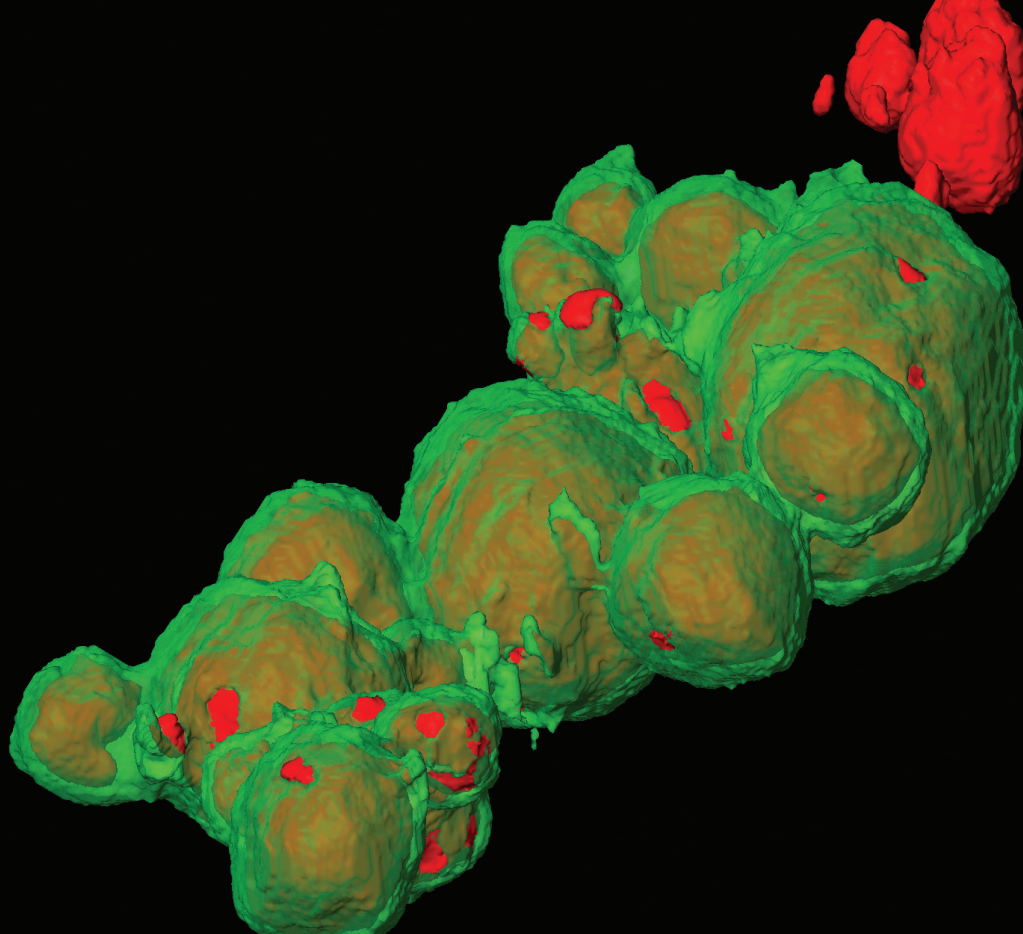
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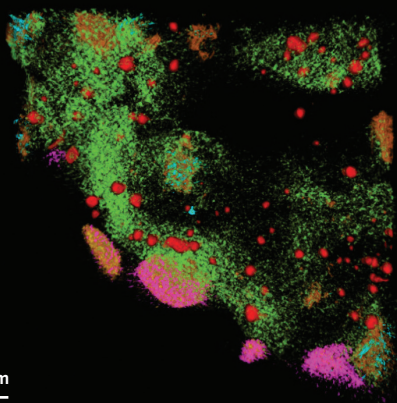
A



50 nm

B

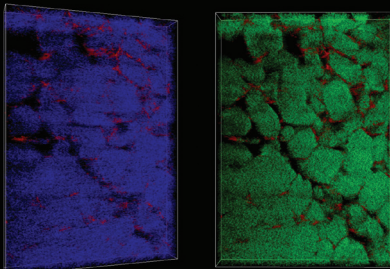
Ce
Zr
P
Pd
Ca



500 nm

C

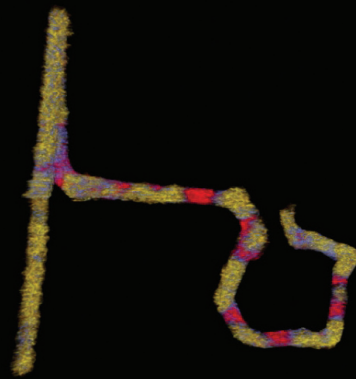
C
Al
Co



400 nm

D

P
Zn
In



50 nm

A: EDS tomogram of Ag-Pt core-shell nanoparticles. Ag cores are shown in the false color of red, covered by green-colored Pt shells, only a few nanometers in thickness. Sample courtesy Prof. Yi Ding and Prof. Jun Luo, Center for Electron Microscopy, Tianjin University of Technology. **B: Vehicle-aged automotive catalyst.** EDS tomogram showing the distribution of Palladium particles (red) relative to other elements. **C: Battery anode material.** EDS tomograms of Carbon-Cobalt and Carbon-Aluminum. **D: EDS tomogram of P-Zn-In nanotubes.** Sample Courtesy of Dr. Reza Shahbazian Yassar, Michigan Tech University.

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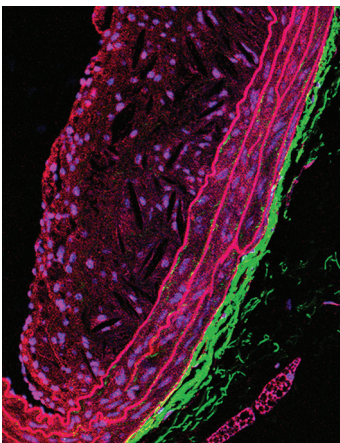
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On the Cover: Second harmonic generation image of atherosclerotic plaque in the thoracic aorta of an apoE knockout mouse. Green = collagen, Red = elastin, blue = nuclei. For further information see Watson and Lessner, pp 589-598.

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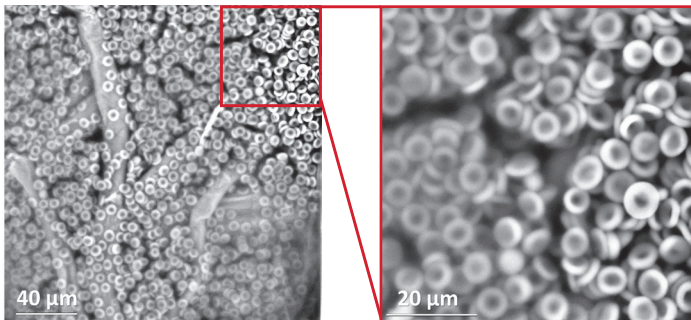
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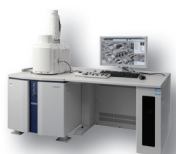
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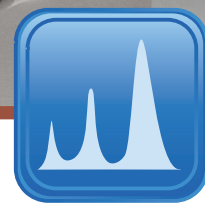
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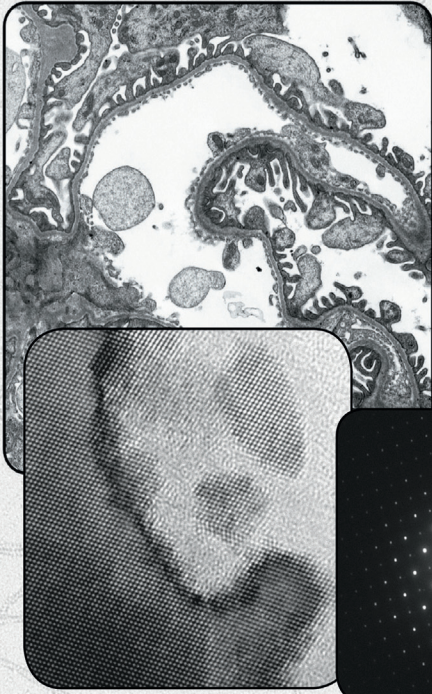
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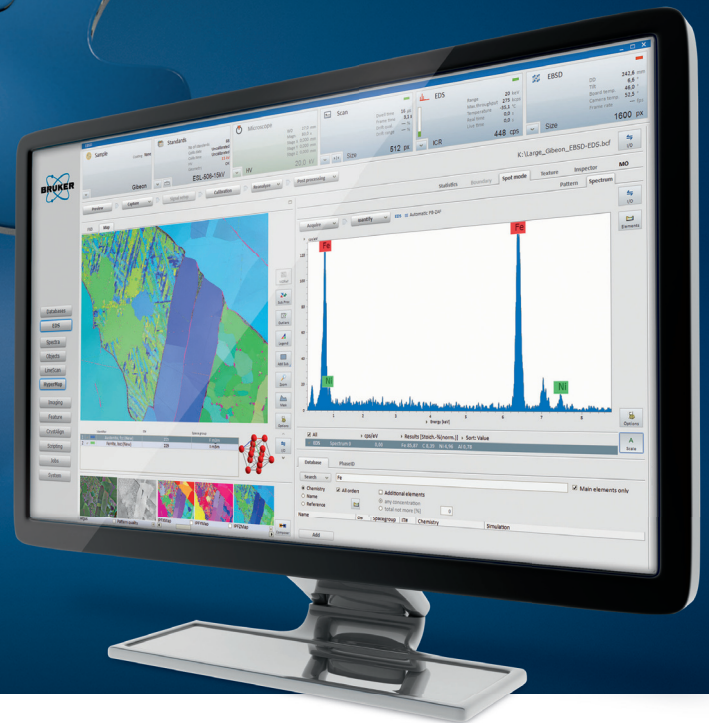
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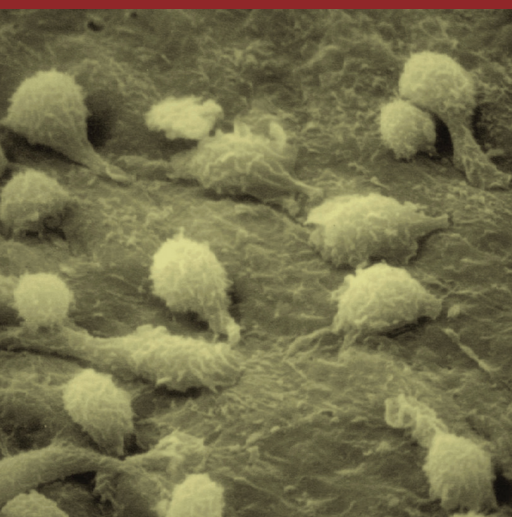


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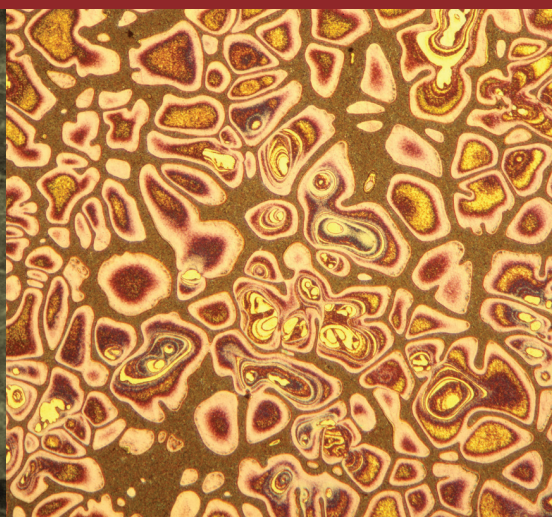
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Software

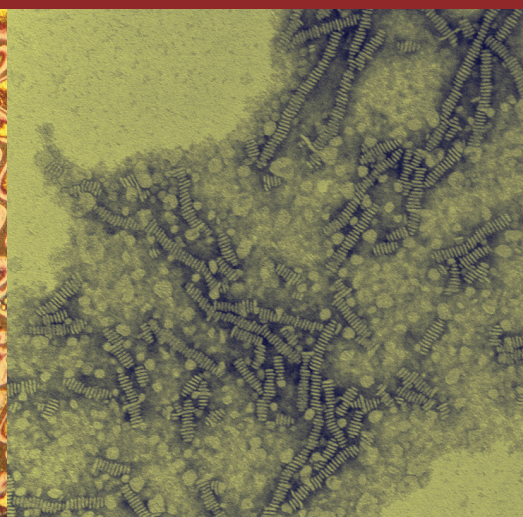
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Monocytes (White Blood Cells) Adhering to the Inside Surface of an Artery as Part of an Inflammatory Reaction. W. Gray (Jay) Jerome, Vanderbilt University



Cast A347 Alloy Made by Semi-solid Melting (Mert Fleming's Development) Weck's Reagent in Bright Field. George Vander Voort, Consultant (Struers Inc.)



High Density Lipoprotein (HDL; the good cholesterol carrier) Stacking Together in Solution. W. Gray (Jay) Jerome, Vanderbilt University



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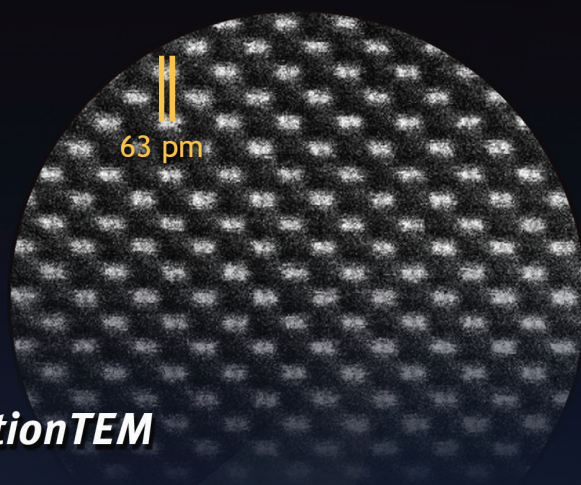
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